



ALTERNATIVE TO PTO/SB/08A/B (09/06)


Substitute for form 1449/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Complete if Known	
				Application Number	10/772,585
				Filing Date	February 6, 2004
				First Named Inventor	Tetsuro ASANO
				Art Unit	2813
				Examiner Name	L. M. Schillinger
				Attorney Docket Number	492322017600
Sheet	1	of	2		

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No.¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code² (if known)			
LS	1.	US-4,339,285	07/1982	Pankove	
	2.	US-4,387,386	06/1983	Garver	
	3.	US-4,626,802	12/1986	Gailus	
	4.	US-4,745,445	05/1988	Mun et al.	
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	6.	US-4,843,440	06/1989	Huang	
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	17.	US-6,002,860	12/1999	Voinigescu et al.	
	18.	US-6,265,756	07/2001	Brocket et al.	
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	23.	US-6,946,891	11-11-2004	Asano et al.	

Examiner Signature	<i>L. M. Schillinger</i>	Date Considered	5/28/07
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Sheet	2	of	2	Attorney Docket Number	492322017600

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	MM-DD-YYYY			
	24.	DE-3334167	04-04-1985	Siemens AG	Corresponds to Cite 8	
	25.	EP-0 140 095	05-08-1985	Siemens AG	Corresponds to Cite 8	
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	28.	EP-0 700 161	03-06-1996	Hitachi, Ltd.		
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	30.	KR-1998-065222	10-15-1998		Corresponds to Cite 16	
	31.	JP-11-220093	08-10-1999	Sanyo Electric Co., Ltd.	Translation of Abstract	

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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
[Signature]	32.	Sze, S.M. (1981). <u>Physics of Semiconductor Devices</u> . New York, NY: John Wiley & Sons. pp. 117-122.	

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Examiner Signature	<i>Laura Schill</i>	Date Considered	5/28/07
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